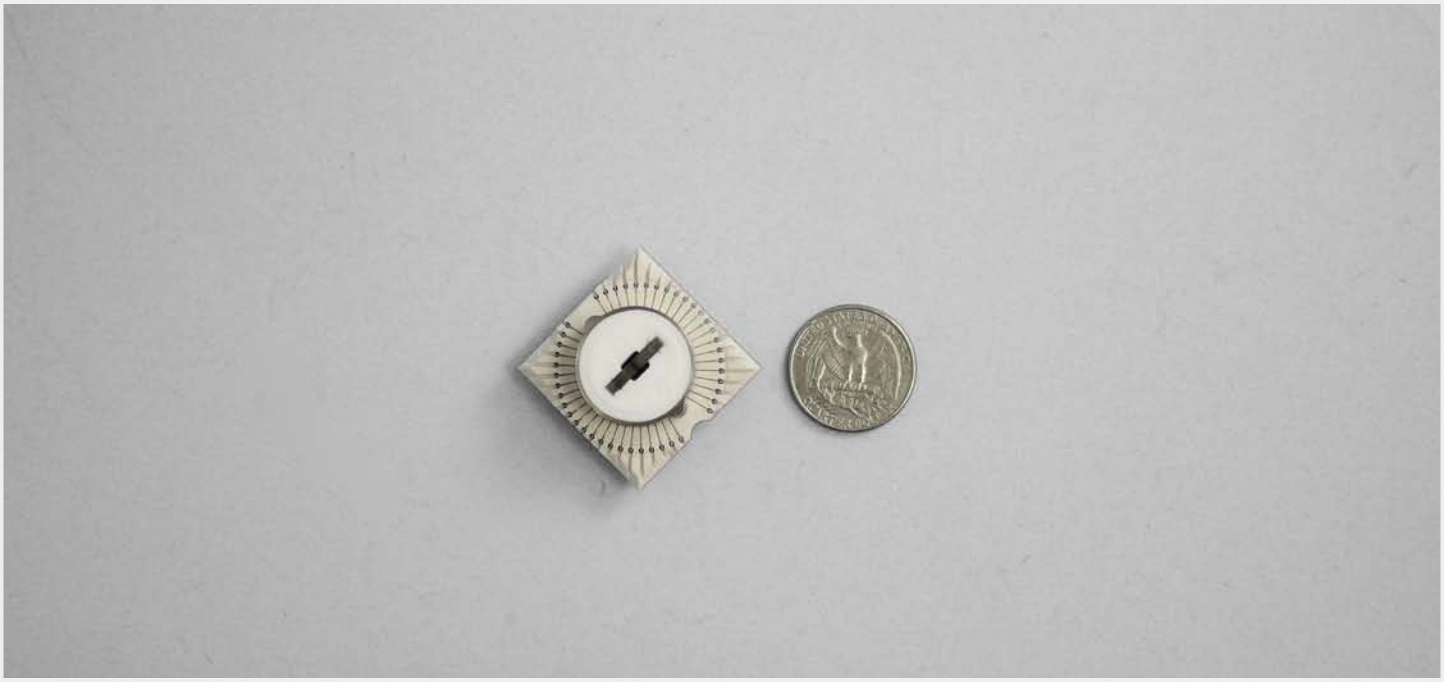
VC20 PROBE CARD

20MM PROBE CARD FOR MODELING & CHARACTERIZATION, PARAMETRIC TEST, AND WAFER LEVEL RELIABILITY



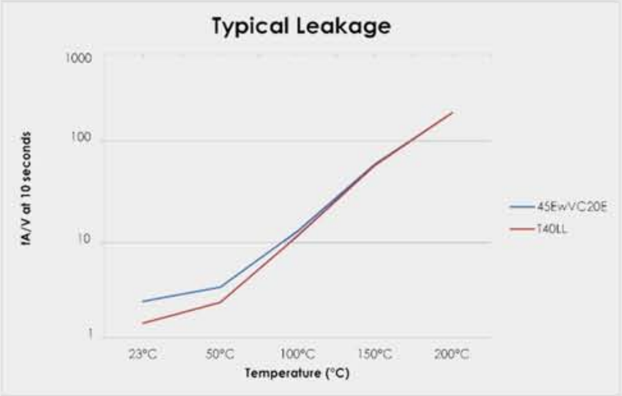
The Element Series VC20 probe card is a highly adaptable solution for a wide variety of tests. Easily use the VC20 in different adapters, or quickly change probe cards for reconfigured wafer layouts in modeling & characterization, wafer level reliability, or parametric test.

The VC20 performs with the same ultra low leakage and high performance of Celadon's standard probe cards.

Low Leakage at 10 seconds:
- Leakage < 5fA/V from -65° to 75°C
- Leakage < 10 fA/V from 75° to 100°C
- Leakage < 50 fA/V from 100° to 150°C
- Leakage < 300 fA/V from 150° to 200°C

- 45E interface makes VC20 probe card compatible with standard 4.5" holders
- 4080E interface makes VC20 probe carrd compatible with Agilent 408x testers
- Up tp 48 single layer probes per card
- Minimum pitch pattern-dependent
- Standard X-Y accuracy 10% pad size
- Standard Z accuracy +/- 5 microns

A VC20 and 45E exhibit the same leakage characteristics as a standard T40LL probe card.



CELADON

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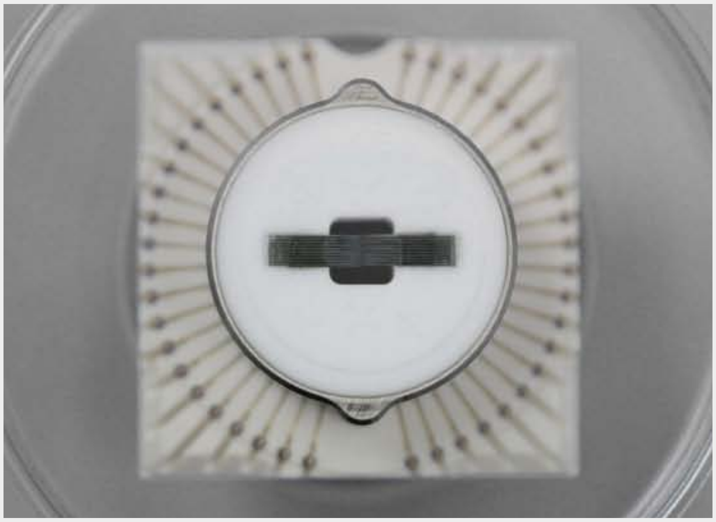

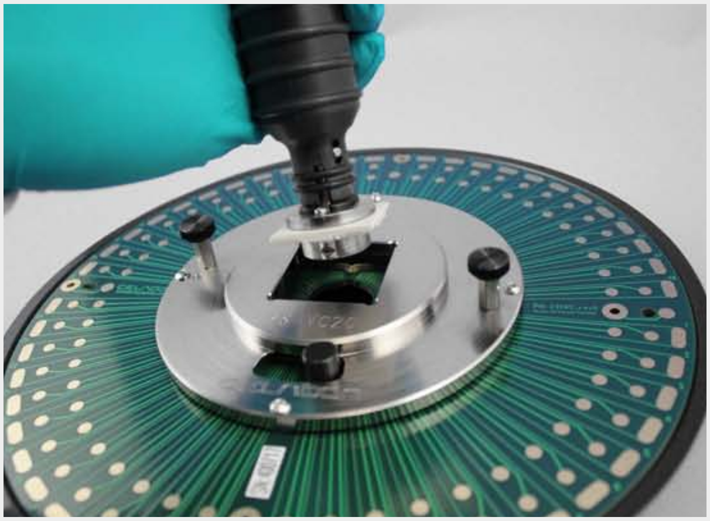

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